

<u>IGC19T60Q</u>

High Speed IGBT3 Chip

Features:

- 600V Trench & Field Stop technology
- high speed switching series third generation
- low V_{CE(sat)}
- low EMI
- low turn-off losses
- positive temperature coefficient
- qualified according to JEDEC for target applications

Recommended for:

- discrete components and modules
- **Applications:**
- uninterruptible power supplies
- welding converters
- converters with high switching frequency



Chip Type	V _{CE}	I Cn	Die Size	Package
IGC19T60Q	600V	40A	4.84 x 3.98 mm ²	sawn on foil

Mechanical Parameters

Mechanical Paramet	ers			
Die size		4.84 x 3.98		
Emitter pad size		See chip drawing	2	
Gate pad size		0.608 x 0.646	mm ²	
Area total		19.26		
Thickness		70	μm	
Wafer size 150			mm	
Max.possible chips per wafer		738		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal ¹⁾		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder (temperature budget: 290°C for 1min. or 260°C for 1.5min.)		
Wire bond		Al, <500μm		
Reject ink dot size		Ø 0.65mm ; max 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C < 6 month		
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert gas, Humidity <25%RH, Temperature 17°C – 25°C, < 6 month		
1)				

¹⁾ collector



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Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, T_{vj} =25 °C	V _{CE}	600	V
DC collector current, limited by $T_{vj max}$	I _C	1)	А
Pulsed collector current, t_p limited by $T_{vj max}^{2}$	I _{c,puls}	120	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction temperature	T _{vj}	-40 +175	°C
Short circuit data 2 $^{3)}$ $V_{GE} = 15V$, $V_{CC} = 400V$, $T_{vj} = 150^{\circ}C$	t _{SC}	5	μs

¹⁾ depending on thermal properties of assembly

²⁾ not subject to production test - verified by design/characterization

³⁾ allowed number of short circuits: <1000; time between short circuits: >1s.

Value Parameter Symbol Conditions Unit min. typ. max. $V_{GE}=0V$, $I_{C}=2$ mA Collector-Emitter breakdown voltage 600 $V_{(BR)CES}$ V_{GE}=15V, *I*_C=40A Collector-Emitter saturation voltage **V**_{CEsat} 1.48 1.95 2.32 V $V_{\rm GE(th)}$ $I_{\rm C}$ =0.58mA , $V_{\rm GE}$ = $V_{\rm CE}$ Gate-Emitter threshold voltage 4.2 5.1 5.6 $V_{CE} = 600 V$, $V_{GE} = 0 V$ 2 Zero gate voltage collector current μA *I*_{CES} $V_{CE}=0V$, $V_{GE}=20V$ Gate-Emitter leakage current 150 nA I_{GES} Integrated gate resistor none r_G Ω

Static Characteristics (tested on wafer), $T_{vj} = 25 \text{ °C}$

Electrical Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
Faranieter	Symbol	Conditions	min.	typ.	max.	Unit
	V	V _{GE} =15V, <i>I</i> _C =40A,		0.5		V
Collector-Emitter saturation voltage	V _{CEsat}	<i>T</i> _{vj} =175 °C		2.5		v
Input capacitance	Cies	V _{CE} =25V,		2500		
		V _{GE} =0V, <i>f</i> =1MHz				pF
Reverse transfer capacitance	Cres	$T_{\rm vj} = 25 ^{\circ}{\rm C}$		75		F.



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Further Electrical Characteristic

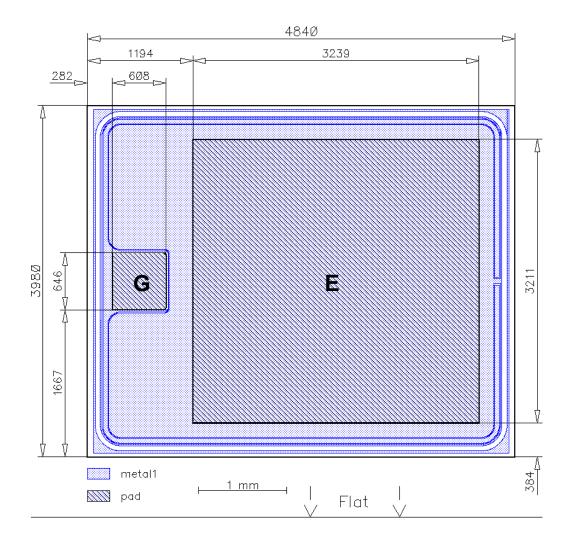
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	IKW40N60H3	Rev 2.2
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IGC19T60Q

Chip Drawing



Die-Size 4840 µm x 3980 um

E = Emitter

G = Gate



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Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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